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- (71) Applicant (for all designated States except US): **BEN GURION UNIVERSITY OF THE NEGEV RESEARCH AND DEVELOPMENT AUTHORITY** [IL/IL]; P. O. Box 653, 84105 Beer-Sheva (IL).
- (72) Inventors; and
- (75) Inventors/Applicants (for US only): **SHCHERBACK, Igor** [IL/IL]; 10/6 David Frishman Street, 84253 Beer-Sheva (IL). **YADID-PECHT, Orly** [IL/IL]; 54 Albert Schweitzer Street, 34995 Haifa (IL).
- (74) Agents: **G.E. EHRlich (1995) LTD.** et al.; 11 Menachem Begin Street, 52521 Ramat Gan (IL).

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(54) Title: OPTICAL SENSOR MEASUREMENT AND CROSSTALK EVALUATION

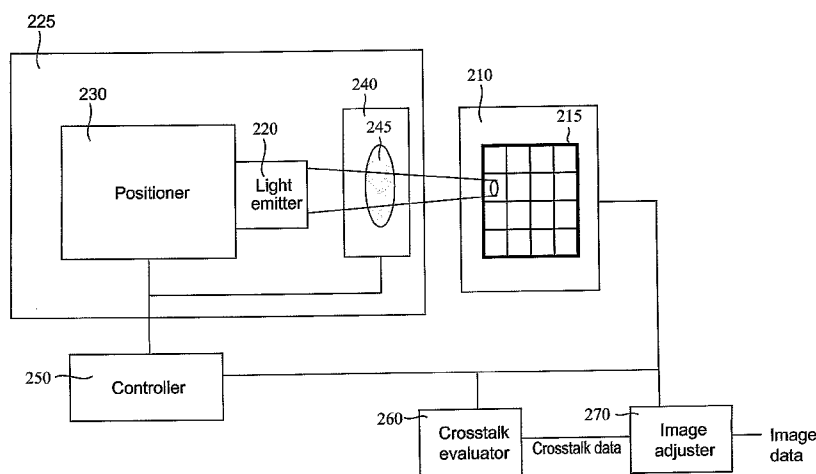


FIG. 2

(57) Abstract: An apparatus for the measurement of optical sensor performance includes a light emitter, a focuser and a controller. The optical sensor comprises a plurality of pixels, which may be arranged as a pixel array. The light emitter projects a light spot onto the sensor. The focuser focuses the light spot onto a specified portion of the sensor in accordance with a control signal. The controller analyzes an output signal of the optical sensor, and generates the control signal to an accuracy substantially confining the light spot to a single pixel in accordance with the analysis.



INTERNATIONAL SEARCH REPORT

International application No.
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A. CLASSIFICATION OF SUBJECT MATTER
IPC(8) - G01V 8/00 (2009.01)
USPC - 250/559.29
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B. FIELDS SEARCHED
Minimum documentation searched (classification system followed by classification symbols)
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Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)
Database: PatBase
Search Terms: light emitter; light spot; photosensitive layer; piezoelectric; crosstalk; optical pixel array; optical sensor

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 6,838,688 B2 (AOKI) 04 January 2005 (04.01.2005) entire document	1-23
A	US 2004/0233271 A1 (NOJIMA et al) 25 November 2004 (25.11.2004) entire document	1-23
A	US 6,831,678 B1 (TRAVIS) 14 December 2004 (14.12.2004) entire document	1-23

Further documents are listed in the continuation of Box C.

* Special categories of cited documents:
 "A" document defining the general state of the art which is not considered to be of particular relevance
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Name and mailing address of the ISA/US
Mail Stop PCT, Attn: ISA/US, Commissioner for Patents
P.O. Box 1450, Alexandria, Virginia 22313-1450
Facsimile No. 571-273-3201

Authorized officer:
Blaine R. Copenheaver
PCT Helpdesk: 571-272-4300
PCT OSP: 571-272-7774